Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
	EZQUERRO SAENZ ET AL.
Examiner	Art Unit
Yunsoo Kim	1644

SEARCHED				
Class	Subclass	Date	Examiner	
530	326	7/6/2005	ΥK	
530	327	7/6/2005	YK	
	<u> </u>			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	-			
SEQ ID	NO:1-10	7/6/2005	YK	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
SEQ ID NOs: 1-10 from stic, completed	7/6/2005	YK		
inventor name search in palm	12/7/2005	ΥK		
foreign priority considered Spain P 9802465 on 11.24.98	12/7/2005	YK		
Allowance conference with C. Chan and approved	12/19/2005	YK		